

Search Notes

Application/Control No.

10/017,417

Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

2664

SEARCHED

Class	Subclass	Date	Examiner
370	331	8/8/2005	BQN
370	468	8/8/2005	BQN
370	346	8/8/2005	BQN
370	333	8/8/2005	BQN
370	335	8/8/2005	BQN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM-TDB) - See Search History Printout.	8/8/2005	BQN
Consider U.S. Patent: 6,339,590 and U.S. Patent: 6,665,281	8/8/2005	BQN